

**REMARKS**

Claims 1-22 remain in the application.

At the outset, the Examiner is thanked for the thorough review and consideration of the pending application. The office action dated December 18, 2003 has been received and its contents carefully reviewed.

In the Office Action, claims 1 and 12 are rejected under 35 U.S.C. § 103(a) as being unpatentable over U.S. Patent No. 6,226,057 to Lee (hereinafter "Lee") in view of U.S. Patent No. 5,953,088 to Hanazawa (hereinafter "Hanazawa"). Claims 3-6, 9-11, 14-17, and 20-22 are rejected over Lee in view of Hanazawa as applied to claims 1 and 12, and further in view of U.S. Patent No. 5,757,444 to Takemura (hereinafter "Takemura"). Applicant gratefully acknowledges the allowability of claims 2, 7, 8, 13, and 19 if rewritten in independent form including all of the limitations of the base claims and any intervening claims. The rejections of these claims is traversed and reconsideration of the claims is respectfully requested in view of the following remarks.

The applicant respectfully submits that Hanazawa is not prior art under 35 U.S.C. § 102(e). Hanazawa was filed on December 23, 1998. The present invention was filed on November 24, 1999, but claims priority to Korean Patent Application No. 1998-51185 filed on November 27, 1998. Applicant will shortly hereafter submit a certified translation of Korean Patent Application No. 1988-51185 to perfect this priority claim. Applicant respectfully requests that Hanazawa be removed as prior art.

Independent claim 1 is allowable over the cited art in that claim 1 recites a combination of elements including, for example "a first pixel electrode disposed in the first pixel region, the

first pixel electrode overlapping one of the first and the second regions of the first data line, and the pixel electrode overlapping one of the first and second regions of the second data line; a second pixel electrode disposed in second pixel region, the second pixel electrode overlapping one of the first and second regions of the second data line that is not overlapped by the first pixel electrode.” Lee does not teach or suggest at least this feature of the claimed invention, which the examiner admits in the Office Action. (See p. 3.) Further, Takemura does not teach or suggest this feature either. Accordingly, Applicant respectfully submits that independent claim 1 and claims 2-11, which depend therefrom are allowable over the cited references.


Independent claim 12 is allowable over the cited art in that claim 12 recites a combination of elements including, for example “forming a first pixel electrode in the first pixel region to overlap one of the first and the second regions of the first data line and to overlap one of the first and second regions of the second data line; and forming a second pixel electrode in the second pixel region to overlap one of the first and the second regions of the second data line that is not overlapped by the first pixel electrode.” Lee does not teach or suggest at least this feature of the claimed invention, which the examiner admits in the Office Action. (See p. 3.) Further, Takemura does not teach or suggest this feature either. Accordingly, Applicant respectfully submits that independent claim 12 and claims 13-22, which depend therefrom are allowable over the cited references.

Applicant believes the application is in condition for allowance and early, favorable action is respectfully solicited. If for any reason the Examiner finds the application other than in condition for allowance, the Examiner is requested to call the undersigned attorney at (202) 496-7500 to discuss the steps necessary for placing the application in condition for allowance. All correspondence should continue to be sent to the below-listed address.

If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time, or any other fees required to complete the filing of this response, may be charged to Deposit Account No. 50-0911. Please credit any overpayment to deposit Account No. 50-0911. A duplicate copy of this sheet is enclosed.

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Respectfully submitted,

  
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PATENT REGISTRATION



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